







**SN74AHCT367** 

#### SCLS418I - JUNE 1998 - REVISED JULY 2024

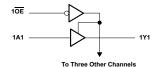
# SN74AHCT367 Hex Buffer and Line Driver with 3-State Output

#### 1 Features

- Inputs are TTL-voltage compatible
- True outputs
- Latch-up performance exceeds 100mA per JESD 78, class II
- ESD protection exceeds JESD 22
  - 2000V human-body model
  - 2000V charged-device model

## 2 Applications

- Telecom Infrastructure
- TVs
- Set Top Boxes
- **Network Switches**
- Wireless Infrastructure
- Electronic Points of Sale



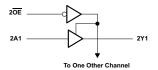
### 3 Description

The SN74AHCT367 device is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

#### Package Information

	PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE(2)	BODY SIZE(3)					
		D (SOIC, 16)	9.9mm × 6mm	9.9mm x 3.90mm					
	SN74AHCT367	DB (SSOP, 16)	6.2mm × 7.8mm	6.2mm x 5.30mm					
	SN/4AHC136/	DGV (TVSOP, 16)	3.6mm × 6.4mm	3.6mm x 4.4mm					
		PW (TSSOP, 16)	5mm × 6.4mm	5.00mm x 4.40mm					

- For more information, see Mechanical, Packaging, and Orderable Information.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.





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# **4 Pin Configuration and Functions**

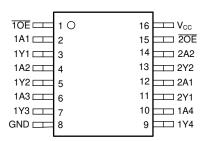


Figure 4-1. D, DB, DGV, or PW Package; 16-Pin SOIC, SSOP, TVSOP, or TSSOP (Top View)

**Table 4-1. Pin Functions** 

PIN		TVDE	DESCRIPTION
NO.	NAME	TYPE	DESCRIPTION
1	1 OE	I	Output Enable 1
2	1A1	I	1A1 Input
3	1Y1	0	1Y1 Output
4	1A2	I	1A2 Input
5	1Y2	0	1Y2 Output
6	1A3	I	1A3 Input
7	1Y3	0	1Y3 Output
8	GND	_	Ground Pin
9	1Y4	0	1Y4 Output
10	1A4	I	1A4 Input
11	2Y1	0	2Y1 Output
12	2A1	I	2A1 Input
13	2Y2	0	2Y2 Output
14	2A2	I	2A2 Input
15	2 OE	I	Output Enable 2
16	V <sub>CC</sub>	_	Power Pin



### **5 Specifications**

### 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5	7	V	
VI	Input voltage range <sup>(2)</sup>		-0.5	7	V
Vo	Output voltage range <sup>(2)</sup>	-0.5	V <sub>CC</sub> + 0.5	V	
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-20	mA
I <sub>OK</sub>	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>		±25	mA
	Continuous current through V <sub>CC</sub> or GND			±75	mA
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Section 5.3. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 5.2 ESD Ratings

			VALUE	UNIT
	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	±2000		
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins <sup>(2)</sup>	±2000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

### **5.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)(1)

		SN74AHCT367		UNIT
		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5.5	V
V <sub>IH</sub>	High-level input voltage	2		V
V <sub>IL</sub>	Low-level Input voltage		0.8	V
VI	Input voltage	0	5.5	V
Vo	Output voltage	0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current		-8	mA
I <sub>OL</sub>	Low-level output current		8	mA
Δt/Δν	Input transition rise or fall rate		20	ns/V
T <sub>A</sub>	Operating free-air temperature	-40	125	°C

All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs (SCBA004).

Product Folder Links: SN74AHCT367

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



#### **5.4 Thermal Information**

			SN74AHCT367				
	THERMAL METRIC(1)	D	DB	DGV	PW	UNIT	
			16	PINS			
R <sub>0JA</sub>	Junction-to-ambient thermal resistance	93.8	103.9	124.5	135.9		
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	54.7	54.3	49.8	70.3		
R <sub>θJB</sub>	Junction-to-board thermal resistance	50.9	54.6	56.2	81.3	°C/W	
ΨЈТ	Junction-to-top characterization parameter	20.8	14.3	5.8	22.5		
ΨЈВ	Junction-to-board characterization parameter	50.7	54.0	55.7	80.8		
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

#### 5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	\ \ <u>\</u>	TA	= 25°C		-40°C to	85°C	-40°C to 1	25°C	UNIT
PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
V	I <sub>OH</sub> = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
V <sub>OH</sub>	I <sub>OH</sub> = -8 mA	4.5 V	3.94			3.8		3.8		V
V	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V
V <sub>OL</sub>	I <sub>OH</sub> = 8 mA	4.5 V			0.36		0.44		0.44	V
l <sub>i</sub>	V <sub>I</sub> = 5.5 V or GND	0 V to 5.5 V			±0.1 <sup>(1)</sup>		±1 <sup>(1)</sup>		±1	μA
l <sub>OZ</sub>	$V_O = V_{CC}$ or GND $V_I (\overline{OE}) = V_{IL}$ or $V_{IH}$	5.5 V			±0.25		±2.5		±2.5	μA
I <sub>CC</sub>	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4	-	40		40	μA
ΔI <sub>CC</sub> (2)	One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	5.5 V			1.35		1.5		1.5	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		2.5	10		10		10	pF
Co	V <sub>O</sub> = V <sub>CC</sub> or GND	5 V		5						pF

- (1) On products compliant to MIL-PRF-38535, this parameter is not production tested at V<sub>CC</sub> = 0 V.
   (2) This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V<sub>CC</sub>.

### 5.6 Switching Characteristics

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V  $\pm$  0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM	FROM TO	LOAD	T <sub>A</sub> = 25	5°C	–40°C to	85°C	–40°C to	125°C	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	TYP	MAX	MIN	MAX	MIN	MAX	UNII
t <sub>PLH</sub>	А	Y	C = 15 pF	2.5 <sup>(1)</sup>	4.8(1)	1	6.5	1	8.5	
t <sub>PHL</sub>		ľ	C <sub>L</sub> = 15 pF	2.5 <sup>(1)</sup>	4.8(1)	1	6.5	1	8.5	ns
t <sub>PZH</sub>	- ŌĒ Y	C <sub>L</sub> = 15 pF	3.5 <sup>(1)</sup>	8(1)	1	9.5	1	9	ns	
t <sub>PZL</sub>	) OE	r	C <sub>L</sub> = 15 pr	2.8(1)	7 <sup>(1)</sup>	1	8.5 <sup>(1)</sup>	1	8	115
t <sub>PHZ</sub>	OE Y		C <sub>1</sub> = 15 pF	3.1 <sup>(1)</sup>	8(1)	1	9.5	1	9	ns
t <sub>PLZ</sub>			- Ομ - 15 βι	2.8(1)	7 <sup>(1)</sup>	1	8.5	1	8	115
t <sub>PLH</sub>	A	Y	C <sub>L</sub> = 50 pF	3.5	5.8	1	7.5	1	9.5	ns
t <sub>PHL</sub>			OL = 30 pi	3.3	5.8	1	7.5	1	9.5	115
t <sub>PZH</sub>	ŌĒ	Υ	C <sub>L</sub> = 50 pF	4.5	9	1	10.5	1	10	ns
t <sub>PZL</sub>			OL = 30 pi	3.7	8	1	9.5	1	9	115
t <sub>PHZ</sub>	ŌĒ	Υ	C <sub>L</sub> = 50 pF	4.1	9	1	10.5	1	10	ns
t <sub>PLZ</sub>		<b>'</b>	OL – 30 PF	3.6	8	1	9.5	1	9	115

On products compliant to MIL-PRF-38535, this parameter is not production tested.



## **5.7 Noise Characteristics**

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C}^{(1)}$ 

	PARAMETER		SN74AHCT367			
	FARAMETER	MIN	TYP	MAX	UNIT	
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.4		V	
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>		-0.4		V	
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>		4.7		V	
V <sub>IH(D)</sub>	High-level dynamic input voltage	2			V	
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.8	V	

<sup>(1)</sup> Characteristics are for surface-mount packages only.

## **5.8 Operating Characteristics**

 $V_{CC}$  = 5 V,  $T_A$  = 25°C

	PARAMETER		CONDITIONS	TYP	UNIT
$C_{pd}$	Power dissipation capacitance	No load,	f = 1 MHz	22	pF

## **5.9 Typical Characteristics**

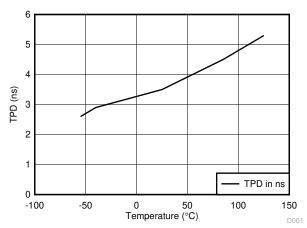


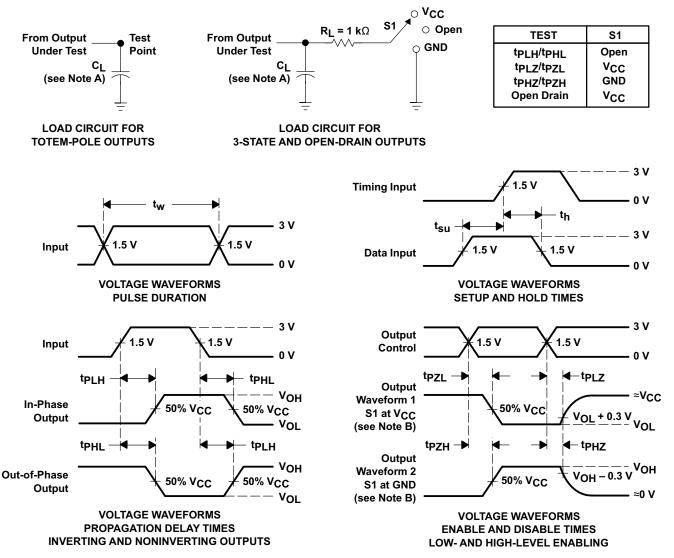
Figure 5-1. TPD vs Temperature, 50 pF Load

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#### **6 Parameter Measurement Information**



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq$  3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.

Figure 6-1. Load Circuit and Voltage Waveforms

### 7 Detailed Description

#### 7.1 Overview

The SN74AHCT367 device is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. This device is organized as a dual 4-line and 2-line buffer/driver with active-low output-enable (1  $\overline{OE}$  and 2  $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes noninverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pull-up resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

### 7.2 Functional Block Diagram



Figure 7-1. Logic Diagram (Positive Logic)

## 7.3 Feature Description

- V<sub>CC</sub> is optimized at 5 V
- Allows up voltage translation from 3.3 V to 5 V
  - Inputs Accept V<sub>IH</sub> levels of 2 V
- Slow edge rates minimize output ringing
- · Inputs are TTL-Voltage compatible

#### 7.4 Device Functional Modes

Table 7-1. Function Table (Each Buffer/Driver)

INP	UTS	OUTPUT
ŌĒ	Α	Y
Н	Х	Z
L	Н	Н
L	L	L

Product Folder Links: SN74AHCT367

## 8 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 8.1 Application Information

SN74AHCT367 is a low-drive CMOS device that can be used for a multitude of bus interface type applications where output ringing is a concern. The low drive and slow edge rates will minimize overshoot and undershoot on the outputs. The input switching levels have been lowered to accommodate TTL inputs of 0.8-V  $V_{IL}$  and 2-V  $V_{IH}$ . This feature makes it Ideal for translating up from 3.3 V to 5 V. Figure 8-2 shows this type of translation.

#### 8.2 Typical Application

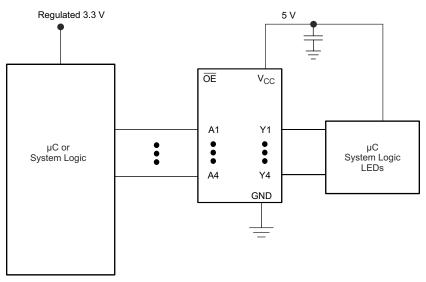


Figure 8-1. Typical Application Schematic

#### 8.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Care should be taken to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads, so routing and load conditions should be considered to prevent ringing.

#### 8.2.2 Detailed Design Procedure

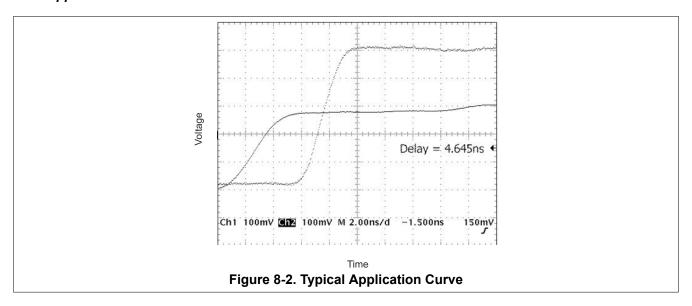
- 1. Recommended Input Conditions
  - For rise time and fall time specifications, see  $\Delta t/\Delta V$  in the Section 5.3 table.
  - For specified High and low levels, see V<sub>IH</sub> and V<sub>IL</sub> in the Section 5.3 table.
  - Inputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V<sub>CC</sub>.
- 2. Recommend Output Conditions
  - Load currents should not exceed 25 mA per output and 75 mA total for the part.
  - Outputs should not be pulled above V<sub>CC</sub>.

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#### 8.2.3 Application Curves



#### 8.3 Power Supply Recommendations

#### 8.4 Layout

#### 8.4.1 Layout Guidelines

When using multiple bit logic devices, inputs should not float. In many cases, functions or parts of functions of digital logic devices are unused. Some examples are when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Figure 8-3 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or  $V_{CC}$ , whichever makes more sense or is more convenient. It is acceptable to float outputs unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the outputs section of the part when asserted. This will not disable the input section of the I/Os so they also cannot float when disabled.



### 8.4.2 Layout Example

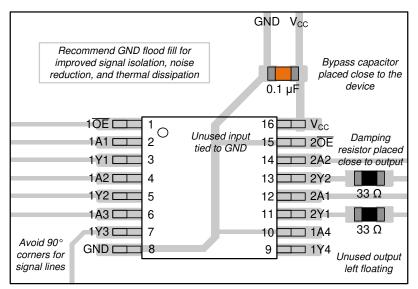


Figure 8-3. Example Layout for the SN74AHCT367 in the PW Package



### 9 Device and Documentation Support

### 9.1 Documentation Support

#### 9.1.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

#### Table 9-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY	
SN74AHCT367	Click here	Click here	Click here	Click here	Click here	

#### 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 9.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 10 Revision History

## Changes from Revision H (December 2014) to Revision I (July 2024) Updated structural layout of data sheet to current standards......1 Updated R0JA values: D = 85.1 to 93.8, PW = 111.5 to 135.9; Updated D and PW packages for R0JC(top), RθJB, ΨJT, ΨJB, and RθJC(bot), all values in °C/W ......5

#### Changes from Revision G (July 2003) to Revision H (December 2014)

**Page** 

Added Applications, Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Typical Characteristics, Feature Description section, Device Functional Modes, Application and

Product Folder Links: SN74AHCT367

	Implementation section, Power Supply Recommendations section, Layout section, Device and
	Documentation Support section, and Mechanical, Packaging, and Orderable Information section
•	Deleted Ordering Information table
•	MAX operating temperature to 125°C in Recommended Operating Conditions table

# 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	<b>Device Marking</b> (4/5)	Samples
SN74AHCT367D	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-40 to 125	AHCT367	
SN74AHCT367DBR	ACTIVE	SSOP	DB	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB367	Samples
SN74AHCT367DGVR	ACTIVE	TVSOP	DGV	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB367	Samples
SN74AHCT367DR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT367	Samples
SN74AHCT367PW	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-40 to 125	HB367	
SN74AHCT367PWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	HB367	Samples
SN74AHCT367PWRG4	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB367	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



## PACKAGE OPTION ADDENDUM

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Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHCT367DBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74AHCT367DGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74AHCT367DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74AHCT367DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74AHCT367DR	SOIC	D	16	2500	330.0	12.4	3.75	3.75	1.15	8.0	12.0	Q1
SN74AHCT367PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT367PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT367PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT367PWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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\*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHCT367DBR	SSOP	DB	16	2000	356.0	356.0	35.0
SN74AHCT367DGVR	TVSOP	DGV	16	2000	356.0	356.0	35.0
SN74AHCT367DR	SOIC	D	16	2500	353.0	353.0	32.0
SN74AHCT367DR	SOIC	D	16	2500	353.0	353.0	32.0
SN74AHCT367DR	SOIC	D	16	2500	340.5	336.1	32.0
SN74AHCT367PWR	TSSOP	PW	16	2000	353.0	353.0	32.0
SN74AHCT367PWR	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74AHCT367PWRG4	TSSOP	PW	16	2000	353.0	353.0	32.0
SN74AHCT367PWRG4	TSSOP	PW	16	2000	356.0	356.0	35.0

### DGV (R-PDSO-G\*\*)

#### **24 PINS SHOWN**

#### **PLASTIC SMALL-OUTLINE**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194

# D (R-PDS0-G16)

### PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.







#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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